

Search Notes



Application/Control No.

10/822,177

Examiner

VanThu Nguyen

Applicant(s)/Patent under
Reexamination

NOGUCHI ET AL.

Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	185.09 o 185.17 x 185.33 x	10/26/2005	VTN
	185.03 x		
	185.11 x		
714	764 x		
	778 x		
11. Update Search 5/26/06 VTN			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Same as above 5/26/06 VTN			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST Search (see print out history)	10/26/2005	VTN
Update search	5/26/06	VTN